

COMMUNICATION

Revealing perovskite formation kinetics during chemical vapour deposition

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1 Amongst a number of deposition methods for perovskite layers,
2 vapour based ones are promising for large area industrial
3 production of solar cells. Different variants of such methods and
4 high efficiencies have been reported recently, but there remains
5 lack of understanding on the formation process of perovskite layers
6 with 2-step vapour deposition. Here, we present a new reactor
7 design for controlled investigation of the reaction kinetics for
8 conversion of evaporated metal halide precursor layer (such as
9 mixture of lead iodide and cesium bromide) into perovskite layer
10 by exposure to an organo-halide (such as formamidinium iodide)
11 vapour under stable isobaric-isothermal conditions. With this new
12 concept of gas flow reversal in tubular reactor, we overcome
13 inherent problem of the lack of control over the precise start and
14 end of the conversion process. We investigated the formation
15 reaction of mixed cation ($\text{Cs}_{0.04}\text{FA}_{0.96}$) PbI_3 perovskite in well-defined
16 intermediate states to elucidate the influence of processing
17 conditions on the kinetics of perovskite and other phase
18 formations. High conversion rate of up to 60 nm/min is achieved
19 with a well-controlled abrupt start and end of the vapor supply.
20 Using our deposition method, a semitransparent solar cell with
21 power conversion efficiency (maximum power tracking) of 9.6% on
22 a designated area of 0.27 cm² is achieved in the initial phase
23 development where the charge extracting layers and interfaces are
24 yet to be optimised.

25 Introduction

26 The past decade has witnessed the unprecedented advances in
27 power conversion efficiency (PCE) of thin film solar cells based
28 on metal halide perovskites (ABX_3 , A = Cs, methylammonium
29 (MA), formamidinium (FA); B = Pb, Sn; X = Cl, Br, I^{1,2}), with a
30 certified efficiency at 25.2% on ~ 0.1 cm².^{3,4} An industrially

promising approach for the deposition of perovskite thin films
is the chemical vapour deposition (CVD)^{5,6}. Although in
literature various technical implementations and also naming
(e.g. H-CVD: hybrid chemical vapour deposition⁷, VASP: vapour
assisted solution processing⁸, ITCVD: in-situ tubular chemical
vapour deposition⁹, LP-CVD: Low pressure CVD¹⁰) of this
method can be found, the underlying principle is the same: An
organo-halide material (e.g. FAI) is sublimed and its vapour is
transported to the substrate, where it reacts with a pre-
deposited metal halide precursor layer (e.g. a CsBr/PbI₂).

While this precursor layers can be deposited from solution^{11,12},
they can also be thermally evaporated, which maintains the
advantage of high-uniformity and scalability. Tong et al.
converted a sequentially evaporated CsBr/PbI₂ stack with FAI
for 100 minutes at 140°C to realize a compositionally graded
absorber and achieved an opaque device with a PCE of 18.2%
(0.09 cm²)¹³. Qiu et al. also employed an all-vapour approach
by converting a co-evaporated CsBr/PbI₂ precursor with FAI
vapour. They realized an opaque mini-module with a designated
area of 91.8 cm² and 9.34% PCE. This corresponds to a loss of
only 1.3%/decade of scaled area when comparing to their
champion efficiency of 13.3% on 0.09 cm².¹⁴

Despite the advances in power conversion efficiency, perovskite
formation kinetics during the CVD process has remained
elusive. The CVD process is usually carried out in a reaction
chamber that can be heated and evacuated to provide suitable
sublimation and reaction conditions. Under such conditions,
both the sublimation and the transport of the organic species
already starts and accelerates during the heat-up period and
also doesn't immediately stop during the cool-down period.
This means that the conversion reaction is not happening under
constant conditions but continuous changes in temperature
and vapour pressure of the organic species are occurring. But in
order to study the perovskite formation kinetics during the CVD
process, stable conditions and a well-defined reaction time
window are required.

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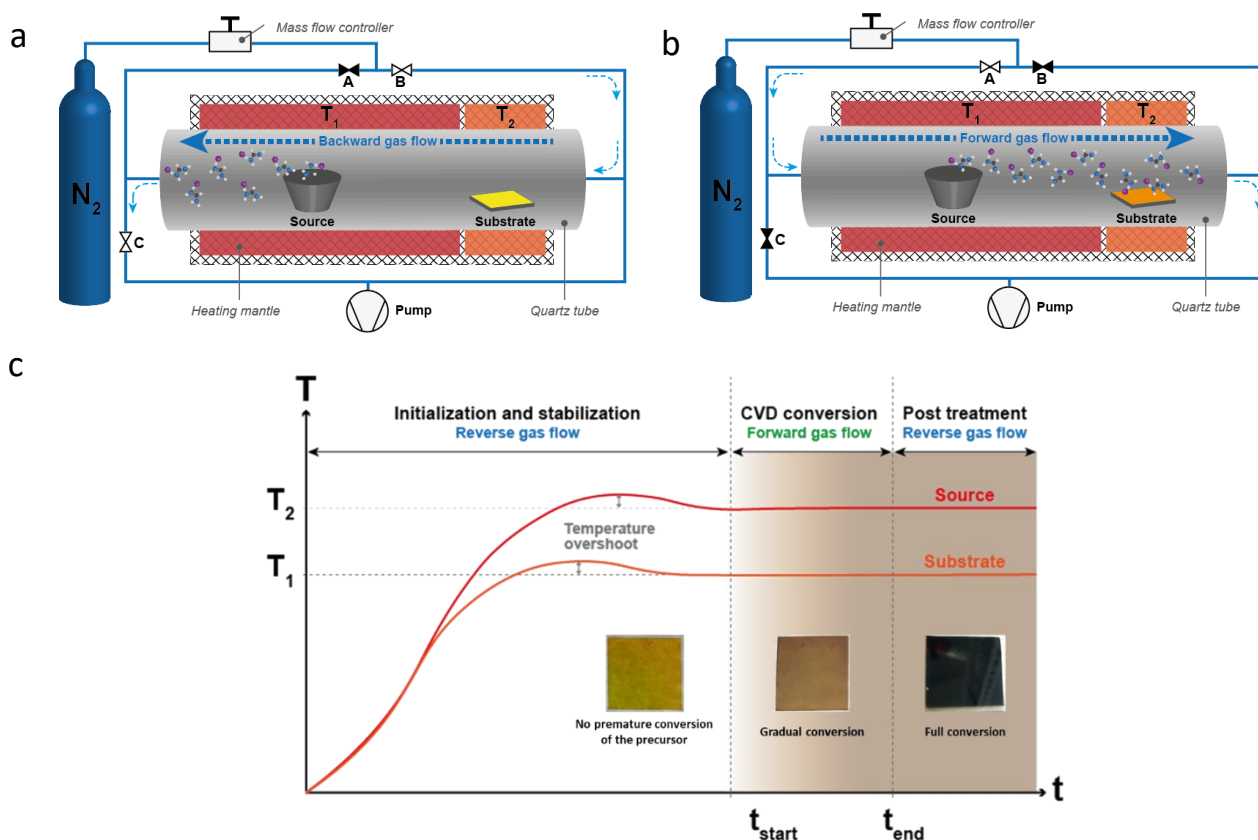


Figure 1: Controlled isothermal-isobaric CVD process. a) and b) Schematic of the CVD reactor, allowing quick reversal of carrier gas flow. Depending on the flow direction, the premature reaction process is prevented before attaining the stabilized thermal conditions. c) Time-temperature-dependent reaction graph with control of carrier gas flow direction: Reverse gas flow allows to stabilize the temperature zones without occurrence of premature conversion reaction. Changing the gas flow direction allows to start and stop the conversion reaction. Additionally, the sample can be kept in the reactor for a post conversion annealing treatment if needed.

67 In this work, we present the deposition of a mixed cation
 68 $(\text{CS}_{0.04}\text{FA}_{0.96})\text{PbI}_3$ perovskite via a hybrid chemical vapour
 69 deposition process where we are able to achieve the required
 70 control by decoupling the heating and reaction step. Through
 71 the systematic study of the perovskite film formation kinetics
 72 we find that the perovskite formation reaction is either mass
 73 transport or diffusion-limited, depending on the temperature
 74 the FAI sublimation zone. Furthermore we find that the
 75 conversion reaction kinetics are not only controlled by the FAI
 76 sublimation temperature but also the substrate temperature.
 77 Understanding the kinetics allows us to deposit high-quality
 78 perovskite film with a growth rate of up to 60 nm/min.
 79 Additionally, we observe the formation of additional phases
 80 besides the desired perovskite under certain processing
 81 conditions. These side reactions have to be avoided and
 82 therefore are important to consider for the CVD deposition of
 83 phase pure perovskite absorbers. As proof-of-concept, the CVD
 84 process was used to fabricate a semi-transparent PSC without
 85 any post-treatment of the absorber or optimization of the
 86 contact layer. The final device exhibits a power conversion
 87 efficiency of 10.6%.

89 Results and discussion

90 Isothermal-isobaric CVD process

91 In the works published so far on the subject of perovskite
 92 absorbers deposited via CVD we encounter systems where the
 93 organic vapour is allowed to come into contact during the
 94 complete process. This means that the conversion already starts
 95 (resp. continues) during the heat-up (resp. cool-down) of the
 96 system. Therefore the conversion is not occurring under
 97 constant conditions (i.e. substrate/source temperature,
 98 pressure, concentration of the organic vapour).

99 To achieve better control over the CVD process we modified the
 100 classical concept of a tubular reactor. Our set-up allows for the
 101 selective injection of the carrier gas from either side of the
 102 reaction chamber. Thus, a gas flow in both directions is possible
 103 – an approach that has yet not been employed in perovskite
 104 research. With our set-up, we can at first have a carrier gas flow
 105 in the reverse direction (i.e., going from the substrate side
 106 towards the source side), as depicted in **Figure 1a**. Under this
 107 condition, we ramp the two heating zones to their distinct
 108 target temperatures with the carrier gas preventing premature
 109 contact between the organic vapour and the precursor. Once
 110 pressure and temperatures stabilized, the flow direction of the
 111 carrier gas is reversed, enabling the vapour and precursor layer
 112 to get into contact (see **Figure 1b**). Reversing the flow direction
 113 a second time allows stopping the conversion reaction.

Table 1: Conditions studied for their effects on reaction kinetics and phase evolution.

| Condition | Substrate temp. T_2 [°C] | Source temp. T_1 [°C] |
|-----------|----------------------------|-------------------------|
| A | 160 | 190 |
| B | 180 | 190 |
| C | 160 | 210 |
| D | 180 | 210 |

114 In short, our CVD setup allows the conversion reaction to
 115 happen in isothermal and isobaric conditions for a well-defined
 116 time window. While this is not expected to directly improve the
 117 quality of the final perovskite layer, this unlocks the possibility
 118 to conduct time-resolved mechanism studies on the effect of
 119 temperature and pressure conditions during the CVD process.
 120 For our study we employed a co-evaporated CsBr/PbI₂ layer
 121 with an atomic percentage of 4% CsBr as confirmed by XPS
 122 photoelectron spectroscopy (XPS; **Figure S1**) and convert it via
 123 our CVD set-up with FAI vapour. This composition was chosen
 124 as cesium and formamidinium based perovskites have shown
 125 high stability and power conversion efficiencies.^{15–17}
 126 Albeit the precursor contains bromine, XPS did not show
 127 presence in the final perovskite (**Figure S2–S3**) as it is replaced
 128 by iodine by ion exchange during the CVD process.

130 Kinetics of the conversion reaction

131 To investigate the reaction kinetics of the CVD process, we
 132 estimated the conversion fraction $\Gamma(t)$ of the precursor layer
 133 after different reaction times t as this gives a measure for the
 134 progress of the reaction. Following the approach of
 135 Ummadisingu et al.¹⁸ the conversion fraction was defined as

$$\Gamma(t) = \frac{A(t)}{A_{fc}} * 100\%$$

137 where $A(t)$ is the absorbance of the mixed perovskite layer after
 138 reaction time t and A_{fc} is the absorbance of a fully converted
 139 layer (~500 nm). This conversion fraction was calculated from
 140 UV-Vis spectroscopy data using the Lambert-Beer
 141 relationship¹⁹. Details on the optical model applied, the
 142 underlying calculations are given in the supplementary
 143 information (**Figure S4–S6**).

144 **Figure 2** shows the conversion fraction as a function of reaction
 145 time for four different temperature conditions, specified in
 146 Error! Reference source not found.. For all the runs precursor
 147 thickness and composition as well as pressure and mass flow of
 148 the carrier gas were kept the same.

149 The fastest kinetics is observed for condition C (160–210), where
 150 a full, homogeneous conversion of a 250 nm CsBr/PbI₂
 151 precursor layer is achieved in only 8 minutes.

152 In literature, the required time of the CVD conversion process is
 153 often between one and three hours^{9,12,20}. This is due to the
 154 slow thermal response of conventional tube furnaces and the
 155 low heating rates that need to be employed to avoid thermal
 156 overshoots. Hoerantner et al. on the other hand, reported a

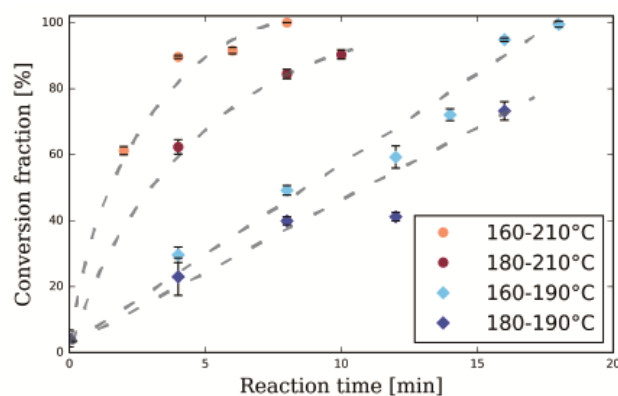


Figure 2: Reaction kinetics of perovskite formation at different conditions shown by the change of the conversion fraction under different conditions with time. The dashed lines serve as guide for the eye.

high-speed vapour deposition technique that only requires a three-minute-long step for the conversion of a 200 nm thick PbI₂ precursor layer into MAPbI₃ perovskite²¹. This already demonstrated that the actual conversion reaction can be achieved at shorter times. In an industrial in-line system, where the substrate would be continuously fed into the reactor and an initialization step is not needed, the actual required conversion time is the key parameter that determines the maximally achievable throughput. For the design of the CVD equipment such knowledge of the reaction kinetics is essential.

One can see that a higher source temperature T_1 strongly increases the conversion rate. This shows that the speed of conversion can be controlled by the sublimation rate of the FAI. Possibly, the rate of conversion could be even further accelerated by increasing the source temperature. But such high kinetics might impede the controllability and reproducibility of the process unless sophisticated temperature and gas flow controls are used.

Comparing the slow and fast (i.e., low resp. high source temperature T_1) conversion regime, we observe two different behaviour. When working with a low source temperature (i.e., condition A (160–190) and B (180–190)), the conversion rate is constant and not affected by the increasing thickness of the perovskite layer. In the case of high source temperature (i.e., condition C (160–210) and D (180–210)) we observe a decrease in the conversion rate with time. This indicates that at a low source temperature, the reaction kinetics are governed by the mass-transport of the FAI vapour. The decrease in conversion rate at a high substrate temperature implies that the solid-state diffusion becomes the dominant factor.

While the influence of the source zone temperature T_1 on the reaction kinetics was anticipated, the influence of the substrate zone temperature T_2 shows the reverse effect: For both slow and fast conversion regime, the reaction speed was lowered when a higher substrate zone temperature T_2 was chosen. A higher substrate temperature T_2 usually is expected to provide more thermodynamic driving force for the reaction between the reactants and also facilitate the interdiffusion, so one could expect to observe an acceleration of the reaction. Nevertheless, it is important to bear in mind that the substrate temperature both affects the condensation dynamics of the FAI vapour and

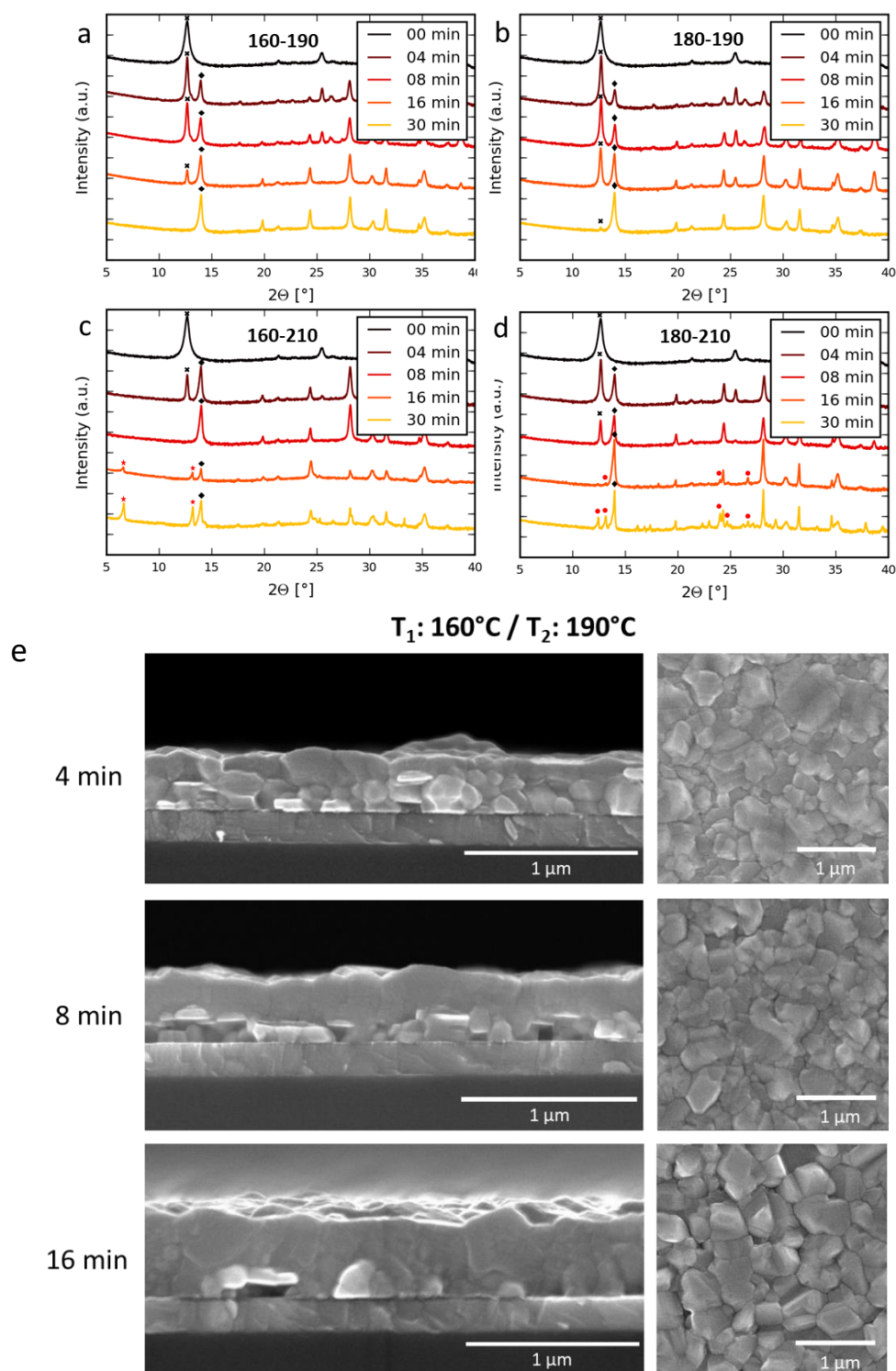


Figure 3: Phase evolution during CVD conversion of perovskite for different conditions of reaction time and temperatures (in $^\circ\text{C}$) of substrate and evaporation source. a) 160-190, b) 180-190, c) 160-210, d) 180-210. During the perovskite formation, the precursor peak (indicated by x) at 12.7° is continuously fading and the perovskite phase peak (indicated by ♦) gains intensity. In c) and d) the formation of additional 'overconversion' phases (indicated by • and ★) is observed once the precursor is converted completely. e) SEM cross section and top-views of layers after 4 min, 8 min and 16 min reaction time with the temperature zone at 160°C and the source zone at 190°C

198 the decomposition reaction of the perovskite. A low 202 effects lead to the accelerated kinetics of the conversion
 199 temperature T_2 will result in higher rate of condensation on 203 reaction at a lower temperature T_2 .
 200 substrate surface (i.e., a higher supply of FAI to the conversion 204
 201 reaction) and a slower decomposition reaction. These two 205

206 Phase evolution of conversion reaction

207 To probe the phase evolution during the CVD process, we
 208 performed X-ray diffraction measurements on the thin films
 209 converted at the four different conditions for various times.
 210 These phase evolutions are depicted in **Figure 3**. The two main
 211 peaks at 12.7° and 14.0° correspond to the PbI_2 (110) and the
 212 (110) perovskite crystalline planes, respectively. They reflect
 213 the conversion process under different conditions: For the fast
 214 conversion regime (i.e., $T_1 = 210^\circ\text{C}$) the peak of the precursor
 215 phase vanishes and the perovskite peak rises very quickly with
 216 time while these effects are more gradual for the slow
 217 conversion regime (i.e., $T_1 = 190^\circ\text{C}$). Again, we observe that a
 218 higher substrate temperature T_2 causes a slower change of the
 219 peak intensities.

220 Under conditions C (160-210) and D (180-210) additional phases
 221 are evolving after the precursor has transformed into
 222 perovskite. Under condition C (160-210), two new peaks start
 223 to show up at 6.6° and 13.2° for a conversion time of 16 minutes
 224 and more. Under condition D (180-210) new peaks are present
 225 at 12.5°, 24.0°, 24.7° and 26.7° when the CVD process is run
 226 16 minutes or more. Formation of these new phases
 227 accompanied by strong changes in optical properties. Initially
 228 the transparent yellow precursor layers turn to a dark
 229 brown/black appearance indicating the conversion
 230 perovskite. Subsequently the appearance would change again
 231 depending on the conditions of the process. Under condition
 232 (160-210) the layers turned to an inhomogeneous yellow
 233 orange hue, while for condition D (180-210) the layers showed
 234 a grey, milky colour and macroscopic cracks. The different
 235 appearances can be seen in **Figure 5f**. We would like to point
 236 out that the apparent inhomogeneity of the precursor layer and
 237 the layers converted at 170-180°C, 160-190°C and 220-200°C in
 238 those photographs stems from the background paper substrate
 239 and is not due to the layers themselves.

240 A possible explanation for the emergence of these additional
 241 peaks could be the condensation and crystallization of pure
 242 source material (i.e., formamidinium iodide) on the sample. The
 243 XRD pattern taken from pure formamidinium iodide powder
 244 displayed in **Figure S7** and no overlap of the diffraction peaks
 245 with the ones observed in our CVD samples could be found.
 246 therefore assume that these additional phases stem from
 247 reaction between the already formed perovskite phase and
 248 formamidinium vapour. This conclusion is in line with work
 249 conducted by Leyden et al. where during CVD-deposition
 250 FAPbI_3 foreign phases together with variations of the optical
 251 appearance were observed, which they attributed to a 'over-
 252 converted' phase²⁰. We term such layers with additional phases as 'over-
 253 converted'. To study the morphological evolution of
 254 perovskite formation, we examined the different stages via
 255 secondary-electron microscopy (SEM). **Figure 3e** shows the
 256 view and cross-sectional SEM micrographs of the layers
 257 processed under condition A (160-190) for 4, 8 and 16 minutes.
 258 The series of cross sections shows that the perovskite phase
 259 forms a continuous layer over the thinning precursor layer
 260 continues growing until only single grains of precursor are
 261 at the perovskite-substrate interface. In general, the conversion

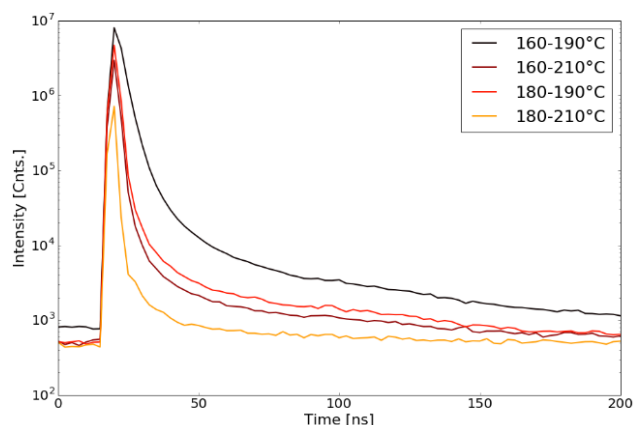


Figure 4: TRPL measurements of perovskite films on fused silica grown under different CVD conditions.

occurs uniformly and creates a flat and pin-hole free perovskite layer. We assessed the grain size distribution for the four different conditions from top-view SEM micrographs (see **Figure S11**), which show that that a faster conversion reaction favours the formation of smaller grains. This observation can be explained by the common theory of crystallization: A faster conversion reaction is expected to create a larger number of nucleation sites where the perovskite crystals can grow, thus creating many small crystallites. Additionally, the reaction time determines the Ostwald ripening. For a slow conversion, the opposite effects, i.e. a lower number of nucleation sites and a higher degree of Ostwald ripening, are expected. The final grains of the perovskite show diameters of a few hundred nanometers. The corresponding micrographs are shown in **Figure S9-S11**. As no differences could be found, we conclude that the final morphology is likely to be mainly determined by other parameters (such as the morphology of the metal halide precursor and the pressure during CVD) than the temperature respectively the growth rate.

Time-resolved photoluminescence results

Figure 4 shows the result of time-resolved photoluminescence (TRPL) measurements conducted on perovskite layers grown on fused silica under the four different conditions A-D. A higher luminescence intensity and a longer carrier lifetime was observed for a slow conversion and a low substrate temperature during the conversion.

The TRPL decay shows a very fast quenching of the photoluminescence. This indicates that the recombination of the charge carriers is strongly dominated by non-radiative recombination. From a bi-exponential fitting we estimated a radiative lifetime of 55 ns for CVD condition A (160-190°C). For the conditions B, C and D no acceptable fitting was possible. Such low lifetimes are quite typical and are still one of the major challenges for vacuum-deposited absorbers^{12,21-23}. Perovskite bulk is commonly assumed to be highly defect tolerant and mainly the surface defects are thought to be responsible for non-radiative recombination of charge carriers^{24,25}. We assume that our vapour phase deposition of perovskite favours

301 the formation of surface defects, which explains the low carrier
 302 lifetimes of the pristine absorbers. 357
 303 358
 304 **Isochronal process map** 359
 305 To gain further insight into the CVD process and the formation
 306 of the 'overconverted' phases, we processed perovskite films 360
 307 a fixed conversion time of 30 minutes and source temperature 361
 308 T_1 ranging from 180° to 220°C and substrate temperatures 362
 309 ranging from 150° to 220°C. The results of the XRD 363
 310 measurements of the fabricated samples are visualized in 364
 311 **Figure 5**. The intensity maps in **Figure 5a** and **b** show the (110) 365
 312 perovskite phase reflection at 14° and the (110) PbI_2 precursor 366
 313 phase reflection at 12.6°, respectively. Additionally, the 367
 314 reflections at 6.6° and at 24° which stem from the 'over- 368
 315 converted' phase were mapped in **Figure 5c** and **d**. 369
 316 One can see that the perovskite phase is present after 370
 317 processing at nearly each condition except for the extreme case 371
 318 of a substrate temperature of 220°C. Meanwhile the precursor 372
 319 is only present for the case of the lowest source temperature 373
 320 (i.e., $T_2 = 180^\circ\text{C}$) or a substrate temperature T_2 equal or above 374
 321 200°C. For the two 'over-converted' phases, we find two 375
 322 different regimes where they start to appear. On the one hand 376
 323 the peak at 6.6° is observed for low substrate temperatures ($T_2 < 170^\circ\text{C}$) 377
 324 together with elevated source temperatures (i.e. $> 190^\circ\text{C}$). On the other hand 378
 325 the peak at 24.0° is observed for medium substrate temperature (i.e., $170^\circ\text{C} < T_2 < 210^\circ\text{C}$) 379
 326 combination with high source temperatures (i.e., $T_1 > 200^\circ\text{C}$). 380
 327 Based on the XRD maps in **Figure 5a-d**, we constructed an 381
 328 isochronal processing map shown in **Figure 5e**. The map 382
 329 visualizes the outcome of the CVD process of 30 minutes, 383
 330 depending on the set temperature of the source zone and 384
 331 substrate zone. 385
 332 386
 333 For a source temperature T_1 below 190°C we define an area 387
 334 'insufficient FAI sublimation'. In this region, the sublimation 388
 335 of the source material (i.e., formamidinium iodide) is very low 389
 336 In consequence, the sample is only weakly converted, even 390
 337 after the 30 minutes of processing time. Clearly, this sets 391
 338 a lower boundary for a useful processing window in which 392
 339 desired perovskite absorber can be fabricated. Another 393
 340 boundary is imposed by the thermal stability of the perovskite 394
 341 For substrate zone temperatures above 200°C there is 395
 342 perovskite but only precursor present after the CVD process 396
 343 This region is named 'decomposition' as the perovskite 397
 344 formed at all – would not withstand the combination of reduced 398
 345 pressure and elevated temperature and decompose. 400
 346 The intriguing aspect of this processing map are the 401
 347 different 'overconversion regions' in which additional 402
 348 unwanted - phases are formed. This does not only impose 403
 349 additional boundaries to the processing window but it provides 404
 350 that the perovskite phase is not the only product that can be 405
 351 formed from cesium bromide, lead iodide and formamidinium 406
 352 iodide. 407
 353 It is important to note that the 'overconverted' phases 408
 354 formed *via* the perovskite phase, after extended reaction time 409
 355 and at high FAI vapour concentrations. This means that 410
 356 thicker precursor layers can be converted without the 411

formation of the overconverted phase if the appropriate CVD
 conditions are chosen. We also do not observe a single-phase
 layer but rather a blend between perovskite and
 'overconverted' phase. These observations indicate that we are
 either dealing with a thermodynamic equilibrium or that the
 formation of the 'overconverted' phases is kinetically hindered.
 We see that at the same source temperature (e.g. 200°C) the
 formation of the 'overconverted' phase can be prevented by
 using a higher substrate zone temperature. This supports the
 assumption of a thermodynamic equilibrium. The higher
 substrate temperature decreases the condensation of the FAI
 vapour, which reduces its chemical potential in the reaction. If
 there were a kinetic hindrance, we would expect that the
 'overconverted' phase is formed faster at a higher temperature.
 It is essential to understand under which conditions this
 'overconversion' reaction occurs for the sake of achieving high
 quality perovskite absorbers. We have already observed that
 the 'overconversion' strongly changes the optical properties of
 the fabricated layer. Clearly this deteriorates the performance
 of the layer when used as an absorber in a photovoltaic device.
 In the work of Leyden et al. they observed similar
 'overconversion' behaviour during the CVD deposition of FAPbI_3
 but did not further investigate under which CVD conditions it
 occurred²⁰. They also showed that the phase formation was
 reversible, which supports the notion of a thermodynamic
 equilibrium. Still the final device performance was impaired by
 the reversal, indicating that it is better to completely avoid the
 overconversion reaction.

Scalability

To demonstrate the scalability of the CVD process, we
 converted a precursor layer deposited on a 5x5 cm² fused silica
 substrate and measured the UV-Vis response and XRD patterns
 in 9 different areas. The XRD shows a single phase perovskite
 layer in all probed areas without any precursor or
 overconversion phase present. From the UV-Vis results we see
 that the perovskite layer is thickest in the middle of the
 substrate and up to 10% thinner in the edge/corner regions.
 This non-uniformity is not stemming from the CVD conversion
 but rather from the PVD deposition of the precursor.
 Profilometry measurements show that the precursor template
 also exhibits a ~10% lower thickness in the edge/corner regions.
 These results suggest that we can uniformly convert precursor
 layers on larger substrates. Still it is important to mention, that
 although a high source temperature (i.e. $T_1 = 210^\circ\text{C}$, high FAI
 vapour concentration) was used, the reaction time had to be
 extended to 20 minutes to achieve full conversion. This shows
 that our experimental CVD set-up is susceptible to the precursor
 area present. Nevertheless, we are convinced that the high
 growth rate achieved on small substrates would be feasible with
 CVD in a uniform manner with appropriate reactor design. The
 corresponding graphs can be found in **Figure S12**.

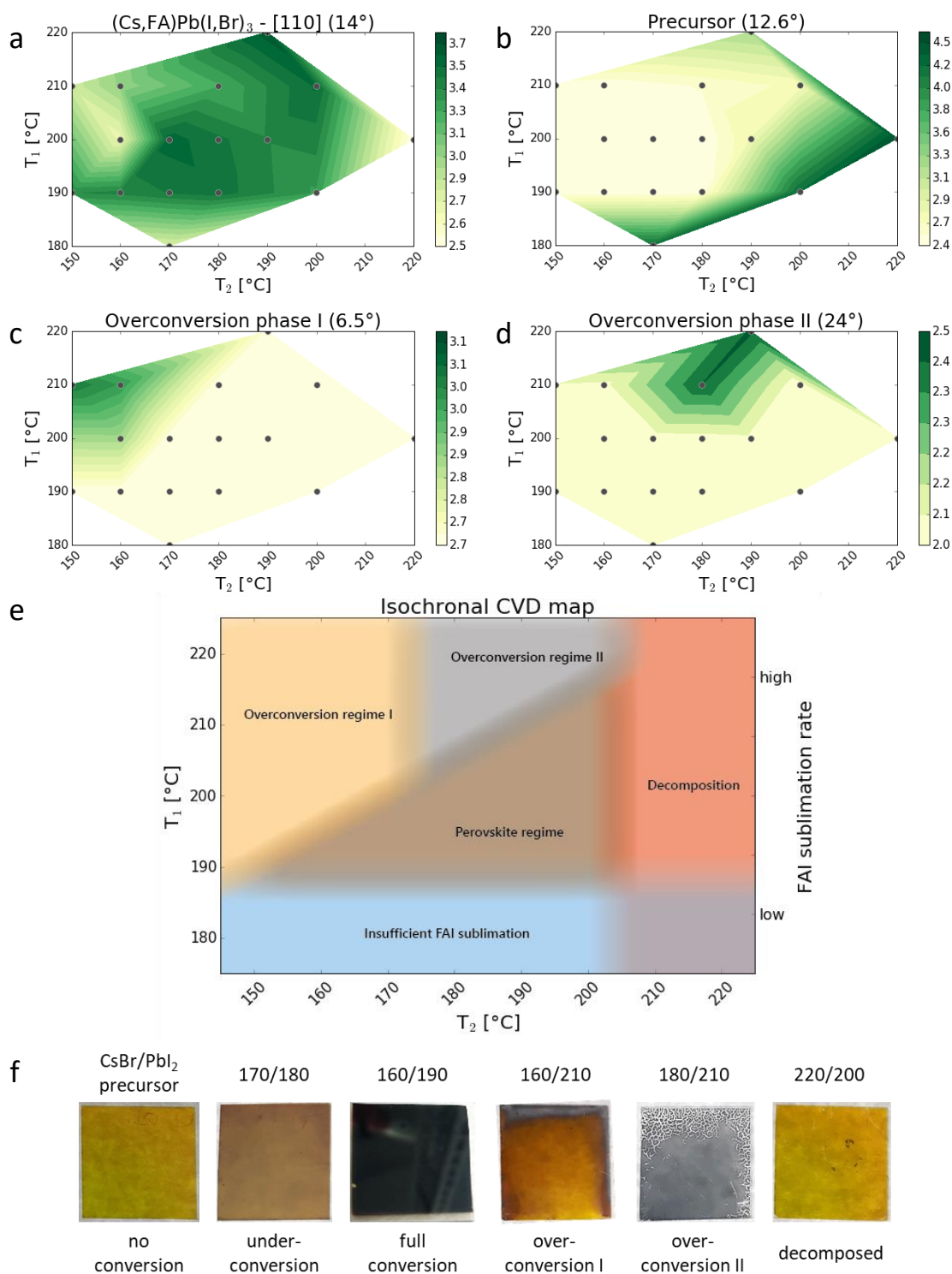


Figure 5: a-d) Intensity maps of selected XRD peaks after 30 minutes CVD processing time. The black dots represent the individual data points. All samples were fabricated and measured under identical conditions, varying only the temperature of the source and substrate zone in the CVD reactor. a) Perovskite (110), b) PbI₂(110), c) overconverted phase I and d) overconverted phase II intensity map. e) Schematic isochronal CVD processing map showing five different regimes. f) Representative images of samples processed in the different regions. The apparent inhomogeneity of the sample stems from the underlying paper substrate used during photography.

412 Device fabrication

413 Using the novel CVD method, we fabricated a semi-transparent
 414 perovskite solar cell with an architecture
 415 ITO/PTAA/Perovskite/PCBM/ZnO(np)/AZO/Ni-Al-grid
 416 Indium tin oxide, PTAA: Poly(triaryl amine), PCBM: Phenyl-C61-

417 butyric acid methyl ester, ZnO(np): Zinc oxide nanoparticles,
 418 AZO: Aluminium-doped zinc oxide)-.

419 In the range of 800-1200 nm an average transmittance of 56.1%
 420 was measured (see **Figure S13**). The low transmittance in the
 421 near infrared region can be explained by the lack of an anti-

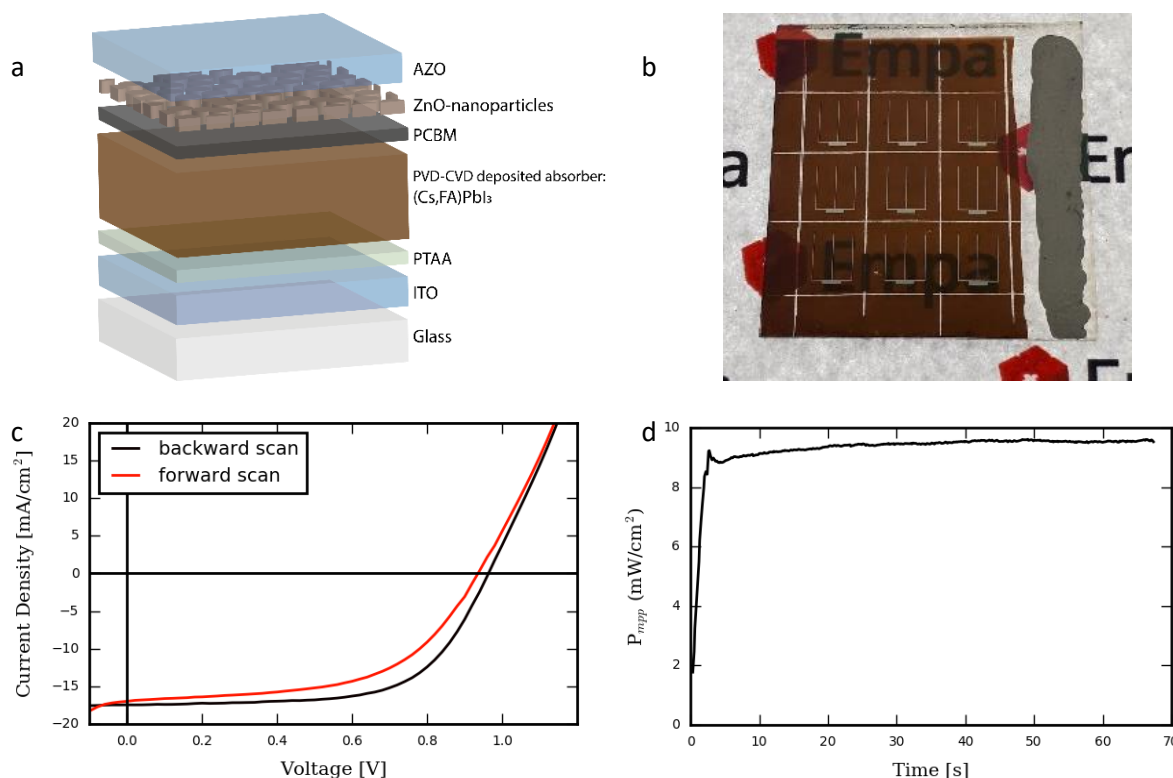


Figure 6: Semitransparent device based on a two-step sequential vapour-deposited perovskite absorber. a) Schematic architecture, b) photograph of the final device, c) J-V characteristics of forward and backward scan and d) MPP measurement of the champion device

422 reflection coating and the high free carrier absorption of the 450
 423 substrate present (see **Figure S14**). This issue could be alleviated 451
 424 by the use of high-mobility hydrogenated indium oxide, which 452
 425 shows excellent NIR transmittance^{26,27}. 453
 426 The cell area of 0.27 cm² was defined by mechanical scribing. 454
 427 schematic of the architecture and a photograph of the device 455
 428 are shown in **Figure 6a** and **b**, respectively. For the conversion 456
 429 of the precursor, the condition A (160-190) and a conversion 457
 430 time of 20 minutes was chosen in order to reach a degree 458
 431 conversion close to 100%. The measured JV characteristics 459
 432 forward and backward direction and the maximum power point 460
 433 (MPP) measurement are shown in **Figure 6c** and **d**, respectively. 461
 434 For our champion device a power conversion efficiency of 10.4% 462
 435 was measured when scanning in backward direction. To the 463
 436 best of our knowledge, this is the highest reported value for the
 437 semi-transparent perovskite solar cell fabricated by the
 438 sequential two-step vapour deposition method. The stabilized
 439 efficiency measured with maximum power point (MPP) tracking
 440 is 9.6%. We attribute this lower performance to the significant
 441 hysteresis revealed by the forward scan (**Figure 6a**). The
 442 statistics of the J-V parameters obtained from the backward
 443 scans of all 9 devices on the substrate are shown in **Figure S15**.
 444 As the device stack has not been optimized we expect that the
 445 device performance can be considerably increased.

446 Conclusions

447 We developed an isobaric-isothermal CVD process that allowed
 448 us to study the reaction kinetics and the phase evolution during
 449 the deposition of mixed (Cs_{0.04}FA_{0.96})PbI₃ perovskite. Our study

shows how the temperature of source and substrate affect the
 conversion reaction kinetics. We demonstrated the uniform
 conversion on 5x5 cm substrates and achieved perovskite films
 with a growth rate of 60 nm/min, which is an important
 parameter from an industrial manufacturing point of view. We
 also show that undesired side reactions can occur during the
 CVD conversion that result in the formation of unfavourable
 phases. This imposes additional boundaries to the process as to
 achieve high quality perovskite layers, these reactions need to
 be avoided by controlling process parameters.
 Using our new sequential vapour deposition method we
 fabricated semi-transparent PSCs with a champion PCE of 9.6%
 on a designated area of 0.27cm².

464 Materials & Method

465 Perovskite layer growth

466 All chemicals were used as received, without any further
 purification or treatment.
 467 To exclude substrate effects, the perovskite layers were always
 grown on the same substrate, namely PTAA coated ITO. The ITO
 substrates ($R_s < 10 \Omega / \square$, Zhuhai Kaivo Optoelectronics Co.)
 468 were washed by hand first, followed by ultra-sonication at 85°C
 in soap water, acetic acid solution, de-salted water and finally
 de-ionized water for 15 minutes each in the order given here.
 469 The ITO substrates were then dried with compressed nitrogen.
 A PTAA layer was prepared by spin-coating a solution of 5 mg
 PTAA (Ossila) in 1 ml of Toluene. 50 μ l of the solution was
 470 dropped onto the 2.5x2.5 cm² ITO substrate spinning at 6000
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478 rpm and the rotation was continued for another 30 seconds.
 479 The layer was dried on a hot plate at 80°C for 5 minutes.
 480 The ITO/PTAA substrate was then transferred to a thermal
 481 evaporation system where PbI_2 (99.999%, Sigma Aldrich) and
 482 CsBr (99.999%, Sigma Aldrich) were co-evaporated at a
 483 evaporation pressure of $3\text{--}6 \times 10^{-8}$ mbar to form the metal
 484 halide precursor layer. The deposition rate of lead iodide
 485 cesium bromide were kept constant at 1.7 \AA s^{-1} and 0.07 \AA s^{-1}
 486 respectively. The targeted deposition thickness of the lead
 487 iodide was set to 250 nm, which corresponds to a thickness
 488 10 nm of the cesium bromide.
 489 The precursor layers were then transferred to the tubular
 490 reactor.
 491 For the CVD conversion, 0.2 g of formamidinium iodide (FAI
 492 >99%, Greatcell Solar Materials) were loaded into a graphite
 493 crucible (Umicore). It was taken care that the FAI powder
 494 evenly spread on the bottom of the crucible to achieve a
 495 constant free surface for sublimation during each run. The
 496 crucible and the precursor coated substrate were placed at the
 497 same position in their individual heating zone for each run. After
 498 loading, the system was pumped down until a pressure of 5
 499 mbar was reached. Then nitrogen (99.999%, PanGas) carrier
 500 was injected via a mass flow controller such that a reverse flow
 501 was established (i.e., valve A closed, valve B and C open, see
 502 **Figure 1a**). The volume flow rate was set to 0.5 mbar L/s
 503 (corresponding to approximately 30 sscm) which resulted in a
 504 equilibrium pressure of 7–8 mbar in the system during the
 505 following process step. With the carrier gas flowing, both
 506 substrate and source heating zones were heated up to their
 507 target temperatures ($T_{\text{substrate}}$: 150–220°C, T_{source} : 180–220°C)
 508 with high heating rate at the beginning and low heating rate
 509 when getting close to the target temperature to avoid
 510 overshooting. Once the target temperature were reached, the
 511 reverse flow was maintained for 10 minutes to establish
 512 thermal equilibrium. After equilibration, the conversion
 513 reaction was started by inverting the flow direction of the
 514 carrier gas to establish downstream flow (i.e., valve A
 515 opened and subsequently valves B and C were closed). After
 516 the desired reaction time had passed, the conversion
 517 halted by once again inverting the carrier gas flow and
 518 establishing the reverse flow. The system was kept under
 519 reverse flow for two minutes before the reactor was vented
 520 with nitrogen, opened and the sample was transferred to a
 521 glove box to cool down and keep exposure to humid air as
 522 as possible.
 523
 524 **Solar cell fabrication**
 525 The solar cell was fabricated with a layer structure of
 526 ITO/PTAA/Perovskite/PCBM/ZnO-nanoparticles/AZO/Ni-Al
 527 grid. The initial ITO/PTAA/Perovskite layer stack was deposited
 528 as described above. For the CVD conversion of the metal halide
 529 precursor, the substrate zone was set to 160°C and the source
 530 zone was set to 190°C and the conversion reaction was allowed
 531 to take place for 20 minutes. The electron-transporting layer
 532 was deposited on top of the perovskite by spin-coating a 20
 533 mg/ml solution of PCBM (PC61BM, 99.5%, SolenneBV). 50 μl of

the solution were dropped at a substrate spinning speed of
 4000 rpm and rotation was continued for 30 seconds. The layer
 was dried for 5 minutes at 80°C. A buffer layer of ZnO
 nanoparticles was then deposited by spin-coating. 50 μl of a
 dispersion of 2.5w% ZnO nanoparticles (particle size: 12 nm,
 Avantama) in isopropanol was dropped at a substrate spinning
 speed of 5000rpm and rotation was continued for 30 seconds.
 The layer was dried for 2 minutes at 80°C. Both spin-coating and
 drying steps were carried out in a nitrogen filled glove box. A
 layer of aluminium doped zinc oxide (AZO) was deposited by RF-
 sputtering as top contact. Subsequently 50 nm of nickel
 followed by 4 μm of aluminium were e-beam evaporated
 through a shadow mask to form the contacting grids. The device
 was finalized by defining the designated area of 0.27 cm^2 by
 mechanical scribing down to the ITO back contact.

Characterization

XRD: X-Ray diffraction patterns were measured on an X'Pert Pro
 in Bragg-Brentano geometry using $\text{Cu-K}\alpha 1$ radiation ($\lambda = 1.5406$
 \AA), scanning from 5 to 80° (2θ) with a step interval of 0.0167°. For the intensity maps the contours were extrapolated from triangulation between the individual data points.

UV-Vis: Reflectance and transmittance measurements were performed using a Shimadzu UV-Vis 3600 spectrophotometer equipped with an integrating sphere. The reflectance data was corrected for the instrumental response stemming from diffuse and specular reflections both on the sample as well as the reflectance measurements were carried out in a wavelength range from 300 to 1500 nm.

SEM: The SEM micrographs were taken with a Hitachi S-4800 Scanning Electron Microscope and a FEI NanoSEM 230 using 5–10 kV acceleration voltage. A thin layer (≈ 1 nm) of Pt was coated on top of the samples to avoid charging effects.

Solar cell characterization: The current density–voltage characteristics of the perovskite solar cell was measured in 4-terminal sensing with a Keithley 2400 source meter. The illumination was provided with a ABA class solar simulator and was calibrated to 1000 W m^{-2} using a certified single crystalline silicon solar cell. The sample stage temperature was kept at 22 °C during the measurements. The J–V measurements were performed in both forward (from –0.1 to 1.5 V) and backward (from 1.5 to –0.1 V) direction. The external quantum efficiency of the cells was measured with a lock-in amplifier. The probing beam was generated by a chopped white source (900 W, halogen lamp, 260 Hz) and a dual grating monochromator. The beam size was adjusted to ensure that the illumination area was fully inside the cell area. The shading effect of metallic grid was taken into account by including middle grid line into the illuminated area. A certified single crystalline silicon solar cell was used as the reference cell. White light bias of approximately 0.1 suns was applied during the measurement with a halogen bias lamp.

TRPL: Time-resolved photoluminescence was measured using the MicroTime 100 system from PicoQuant. A 639 nm pulsed laser diode (pulse width ~ 100 ps) was used. The excitation density was $2 \cdot 10^{12}$ photons· cm^{-2} ·pulse $^{-1}$ ($\sim 3.1 \text{ J s}^{-1} \cdot \text{cm}^{-2}$). The

- 590 spot size was measured by a NanoScan2 beam profiler resulting
591 in ~ 130 μm diameter. Acquisition times were 60 seconds and
592 the pulse frequency 3 MHz. For the fitting procedure a bi-
593 exponential decay was used and the first 35 ns after the signal
594 peak were neglected.
- 595 **XPS:** X-ray photoelectron spectroscopy was performed using a
596 Quantum2000 system from Physical Electronics with a
597 monochromatic Al K_{α} source (1486.6 eV) and a base pressure
598 below $8 \cdot 10^{-9}$ mbar. Survey spectra were recorded with a
599 energy step size of 0.4 eV and a pass energy of 93.90 eV.
600 Composition of the samples was analyzed using the MultiPak
601 software.
- 602
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- 614
- 615 **Conflicts of interest**
- 616 There are no conflicts to declare.
- 617 **Notes and references**
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